

Set Name Query
side by sideHit Count Set Name
result set

DB=USPT,PGPB,JPAB,EPAB,DWPI,TDBD; PLUR=YES; OP=ADJ

<u>L6</u>	L3 and (scan\$ or label\$)	13	<u>L6</u>
<u>L5</u>	L3 and scan\$	9	<u>L5</u>
<u>L4</u>	L3 and executable?	2	<u>L4</u>
<u>L3</u>	L2 not l1	21	<u>L3</u> reviewed all
<u>L2</u>	(old adj1 (program? or file?)) and (new adj1 (program? or file?)) and difference?	21	<u>L2</u>
<u>L1</u>	(difference near5 extract\$) near3 program?	3	<u>L1</u> Scanned all

END OF SEARCH HISTORY

[> home](#) [> about](#) [> feedback](#) [> logout](#)

US Patent & Trademark Office

Search Results

Search Results for: [(old <near/1> program?) and (new <near/1> program?) and difference?]

Found 7 of 100,786 searched. → Rerun within the Portal

Scanned all
Search within Results

[GO](#)[> Advanced Search](#) [> Search Help/Tips](#)

Sort by: [Title](#) [Publication](#) [Publication Date](#) [Score](#) [Binder](#)

Results 1 - 7 of 7 [short listing](#)

1 Identifying the semantic and textual differences between two 100%

versions of a program

Susan Horwitz

ACM SIGPLAN Notices , Proceedings of the conference on Programming language design and implementation June 1990

Volume 25 Issue 6

Text-based file comparators (e.g., the Unix utility diff), are very general tools that can be applied to arbitrary files. However, using such tools to compare programs can be unsatisfactory because their only notion of change is based on program text rather than program behavior. This paper describes a technique for comparing two versions of a program, determining which program components r ...

2 Session 4 (full technical papers): evolution patterns and models: 100%

Evolution patterns of open-source software systems and communities

Kumiyo Nakakoji , Yasuhiro Yamamoto , Yoshiyuki Nishinaka , Kouichi Kishida , Yunwen Ye

Proceedings of the workshop on Principles of software evolution May 2002

Open-Source Software (OSS) development is regarded as a successful model of encouraging "natural product evolution". To understand how this "natural product evolution" happens, we have

IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE

Membership Publications/Services Standards Conferences Careers/Jobs

Welcome
United States Patent and Trademark Office

Help FAQ Terms IEEE Peer Review

Quick Links

» Search

Welcome to IEEE Xplore®

Your search matched [0] of [790210] documents.

- Home
- What Can I Access?
- Log-out

Tables of Contents

- Journals & Magazines
- Conference Proceedings
- Standards

Search

- By Author
- Basic
- Advanced

Member Services

- Join IEEE
- Establish IEEE Web Account

Print Format

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#)
[Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#)
[No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2002 IEEE — All rights reserved